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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I ² C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, SWPMI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, LCD, PWM, WDT
Number of I/O	114
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 24x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l486zgt3

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Table 4. STM32L486xx modes overview

Mode	Regulator ⁽¹⁾	CPU	Flash	SRAM	Clocks	DMA & Peripherals ⁽²⁾	Wakeup source	Consumption ⁽³⁾	Wakeup time
Run	Range 1	Yes	ON ⁽⁴⁾	ON	Any	All	N/A	112 µA/MHz	N/A
	Range2					All except OTG_FS, RNG		100 µA/MHz	
LPRun	LPR	Yes	ON ⁽⁴⁾	ON	Any except PLL	All except OTG_FS, RNG	N/A	136 µA/MHz	to Range 1: 4 µs to Range 2: 64 µs
Sleep	Range 1	No	ON ⁽⁴⁾	ON ⁽⁵⁾	Any	All	Any interrupt or event	37 µA/MHz	6 cycles
	Range 2					All except OTG_FS, RNG		35 µA/MHz	6 cycles
LPSleep	LPR	No	ON ⁽⁴⁾	ON ⁽⁵⁾	Any except PLL	All except OTG_FS, RNG	Any interrupt or event	40 µA/MHz	6 cycles
Stop 0	Range 1	No	Off	ON	LSE LSI	BOR, PVD, PVM RTC, LCD,IWDG COMPx (x=1,2) DACx (x=1,2) OPAMPx (x=1,2) USARTx (x=1...5) ⁽⁶⁾ LPUART1 ⁽⁶⁾ I2Cx (x=1...3) ⁽⁷⁾ LPTIMx (x=1,2) *** All other peripherals are frozen.	Reset pin, all I/Os BOR, PVD, PVM RTC, LCD,IWDG COMPx (x=1..2) USARTx (x=1...5) ⁽⁶⁾ LPUART1 ⁽⁶⁾ I2Cx (x=1...3) ⁽⁷⁾ LPTIMx (x=1,2) OTG_FS ⁽⁸⁾ SWPMI1 ⁽⁹⁾	108 µA	0.7 µs in SRAM 4.5 µs in Flash
	Range 2								

3.12 General-purpose inputs/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. Fast I/O toggling can be achieved thanks to their mapping on the AHB2 bus.

The I/Os alternate function configuration can be locked if needed following a specific sequence in order to avoid spurious writing to the I/Os registers.

3.13 Direct memory access controller (DMA)

The device embeds 2 DMAs. Refer to [Table 7: DMA implementation](#) for the features implementation.

Direct memory access (DMA) is used in order to provide high-speed data transfer between peripherals and memory as well as memory to memory. Data can be quickly moved by DMA without any CPU actions. This keeps CPU resources free for other operations.

The two DMA controllers have 14 channels in total, each dedicated to managing memory access requests from one or more peripherals. Each has an arbiter for handling the priority between DMA requests.

The DMA supports:

- 14 independently configurable channels (requests)
- Each channel is connected to dedicated hardware DMA requests, software trigger is also supported on each channel. This configuration is done by software.
- Priorities between requests from channels of one DMA are software programmable (4 levels consisting of very high, high, medium, low) or hardware in case of equality (request 1 has priority over request 2, etc.)
- Independent source and destination transfer size (byte, half word, word), emulating packing and unpacking. Source/destination addresses must be aligned on the data size.
- Support for circular buffer management
- 3 event flags (DMA Half Transfer, DMA Transfer complete and DMA Transfer Error) logically ORed together in a single interrupt request for each channel
- Memory-to-memory transfer
- Peripheral-to-memory and memory-to-peripheral, and peripheral-to-peripheral transfers
- Access to Flash, SRAM, APB and AHB peripherals as source and destination
- Programmable number of data to be transferred: up to 65536.

Table 7. DMA implementation

DMA features	DMA1	DMA2
Number of regular channels	7	7

This low-power timer supports the following features:

- 16-bit up counter with 16-bit autoreload register
- 16-bit compare register
- Configurable output: pulse, PWM
- Continuous/ one shot mode
- Selectable software/hardware input trigger
- Selectable clock source
 - Internal clock sources: LSE, LSI, HSI16 or APB clock
 - External clock source over LPTIM input (working even with no internal clock source running, used by pulse counter application).
- Programmable digital glitch filter
- Encoder mode (LPTIM1 only)

3.25.5 Infrared interface (IRTIM)

The STM32L486xx includes one infrared interface (IRTIM). It can be used with an infrared LED to perform remote control functions. It uses TIM16 and TIM17 output channels to generate output signal waveforms on IR_OUT pin.

3.25.6 Independent watchdog (IWDG)

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 32 kHz internal RC (LSI) and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

3.25.7 System window watchdog (WWDG)

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

3.25.8 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

3.30 Serial peripheral interface (SPI)

Three SPI interfaces allow communication up to 40 Mbits/s in master and up to 24 Mbits/s slave modes, in half-duplex, full-duplex and simplex modes. The 3-bit prescaler gives 8 master mode frequencies and the frame size is configurable from 4 bits to 16 bits. The SPI interfaces support NSS pulse mode, TI mode and Hardware CRC calculation.

All SPI interfaces can be served by the DMA controller.

3.31 Serial audio interfaces (SAI)

The device embeds 2 SAI. Refer to [Table 13: SAI implementation](#) for the features implementation. The SAI bus interface handles communications between the microcontroller and the serial audio protocol.

The SAI peripheral supports:

- Two independent audio sub-blocks which can be transmitters or receivers with their respective FIFO.
- 8-word integrated FIFOs for each audio sub-block.
- Synchronous or asynchronous mode between the audio sub-blocks.
- Master or slave configuration independent for both audio sub-blocks.
- Clock generator for each audio block to target independent audio frequency sampling when both audio sub-blocks are configured in master mode.
- Data size configurable: 8-, 10-, 16-, 20-, 24-, 32-bit.
- Peripheral with large configurability and flexibility allowing to target as example the following audio protocol: I2S, LSB or MSB-justified, PCM/DSP, TDM, AC'97 and SPDIF out.
- Up to 16 slots available with configurable size and with the possibility to select which ones are active in the audio frame.
- Number of bits by frame may be configurable.
- Frame synchronization active level configurable (offset, bit length, level).
- First active bit position in the slot is configurable.
- LSB first or MSB first for data transfer.
- Mute mode.
- Stereo/Mono audio frame capability.
- Communication clock strobing edge configurable (SCK).
- Error flags with associated interrupts if enabled respectively.
 - Overrun and underrun detection.
 - Anticipated frame synchronization signal detection in slave mode.
 - Late frame synchronization signal detection in slave mode.
 - Codec not ready for the AC'97 mode in reception.
- Interruption sources when enabled:
 - Errors.
 - FIFO requests.
- DMA interface with 2 dedicated channels to handle access to the dedicated integrated FIFO of each SAI audio sub-block.

Table 15. STM32L486xx pin definitions (continued)

Pin Number					Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WLCSP72	LQFP100	UFBGA132	LQFP144					Alternate functions	Additional functions
62	E8	96	B3	140	PB9	I/O	FT_fl	-	IR_OUT, TIM4_CH4, I2C1_SDA, SPI2_NSS, DFSDM1_CKIN6, CAN1_TX, LCD_COM3, SDMMC1_D5, SAI1_FS_A, TIM17_CH1, EVENTOUT	-
-	-	97	C3	141	PE0	I/O	FT_I	-	TIM4_ETR, LCD_SEG36, FMC_NBL0, TIM16_CH1, EVENTOUT	-
-	-	98	A2	142	PE1	I/O	FT_I	-	LCD_SEG37, FMC_NBL1, TIM17_CH1, EVENTOUT	-
63	A8	99	D3	143	VSS	S	-	-	-	-
64	A9	100	C4	144	VDD	S	-	-	-	-

- PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited:
 - The speed should not exceed 2 MHz with a maximum load of 30 pF
 - These GPIOs must not be used as current sources (e.g. to drive an LED).
- After a Backup domain power-up, PC13, PC14 and PC15 operate as GPIOs. Their function then depends on the content of the RTC registers which are not reset by the system reset. For details on how to manage these GPIOs, refer to the Backup domain and RTC register descriptions in the RM0351 reference manual.
- After reset, these pins are configured as JTAG/SW debug alternate functions, and the internal pull-up on PA15, PA13, PB4 pins and the internal pull-down on PA14 pin are activated.

Table 17. Alternate function AF8 to AF15 (for AF0 to AF7 see [Table 16](#)) (continued)

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4, UART5, LPUART1	CAN1, TSC	OTG_FS, QUADSPI	LCD	SDMMC1, COMP1, COMP2, FMC, SWPMI1	SAI1, SAI2	TIM2, TIM15, TIM16, TIM17, LPTIM2	EVENTOUT
Port B	PB0	-	-	QUADSPI_BK1_IO1	LCD_SEG5	COMP1_OUT	-	-	EVENTOUT
	PB1	-	-	QUADSPI_BK1_IO0	LCD_SEG6	-	-	LPTIM2_IN1	EVENTOUT
	PB2	-	-	-	-	-	-	-	EVENTOUT
	PB3	-	-	-	LCD_SEG7	-	SAI1_SCK_B	-	EVENTOUT
	PB4	UART5_RTS_DE	TSC_G2_IO1	-	LCD_SEG8	-	SAI1_MCLK_B	TIM17_BKIN	EVENTOUT
	PB5	UART5_CTS	TSC_G2_IO2	-	LCD_SEG9	COMP2_OUT	SAI1_SD_B	TIM16_BKIN	EVENTOUT
	PB6	-	TSC_G2_IO3	-	-	TIM8_BKIN2_COMP2	SAI1_FS_B	TIM16_CH1N	EVENTOUT
	PB7	UART4_CTS	TSC_G2_IO4	-	LCD_SEG21	FMC_NL	TIM8_BKIN_COMP1	TIM17_CH1N	EVENTOUT
	PB8	-	CAN1_RX	-	LCD_SEG16	SDMMC1_D4	SAI1_MCLK_A	TIM16_CH1	EVENTOUT
	PB9	-	CAN1_TX	-	LCD_COM3	SDMMC1_D5	SAI1_FS_A	TIM17_CH1	EVENTOUT
	PB10	LPUART1_RX	-	QUADSPI_CLK	LCD_SEG10	COMP1_OUT	SAI1_SCK_A	-	EVENTOUT
	PB11	LPUART1_TX	-	QUADSPI_NCS	LCD_SEG11	COMP2_OUT	-	-	EVENTOUT
	PB12	LPUART1_RTS_DE	TSC_G1_IO1	-	LCD_SEG12	SWPMI1_IO	SAI2_FS_A	TIM15_BKIN	EVENTOUT
	PB13	LPUART1_CTS	TSC_G1_IO2	-	LCD_SEG13	SWPMI1_TX	SAI2_SCK_A	TIM15_CH1N	EVENTOUT
	PB14	-	TSC_G1_IO3	-	LCD_SEG14	SWPMI1_RX	SAI2_MCLK_A	TIM15_CH1	EVENTOUT
	PB15	-	TSC_G1_IO4	-	LCD_SEG15	SWPMI1_SUSPEND	SAI2_SD_A	TIM15_CH2	EVENTOUT

Table 34. Current consumption in Stop 2 mode (continued)

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (Stop 2 with RTC)	Supply current in Stop 2 mode, RTC enabled	RTC clocked by LSI, LCD disabled	1.8 V	1.42	4.04	15	34.9	77.2	3.1	10	38	87	193	μA
			2.4 V	1.5	4.22	15.4	35.7	79.2	3.2	11	39	89	198	
			3 V	1.64	4.37	15.8	36.7	81.4	3.4	11	40	92	204	
			3.6 V	1.79	4.65	16.6	38.4	85.4	3.6	12	42	96	214	
		RTC clocked by LSI, LCD enabled ⁽³⁾	1.8 V	1.53	4.07	15.1	35.1	77.4	3.3	10	38	88	194	
			2.4 V	1.62	4.32	15.5	35.9	79.5	3.4	11	39	90	199	
			3 V	1.69	4.43	15.9	36.8	81.7	3.5	11	40	92	204	
			3.6 V	1.86	4.65	16.7	38.5	85.5	3.7	12	42	96	214	
		RTC clocked by LSE bypassed at 32768Hz, LCD disabled	1.8 V	1.5	4.13	15.2	35.3	77.6	3.2	10	38	88	194	
			2.4 V	1.63	4.33	15.6	36	79.6	3.4	11	39	90	199	
			3 V	1.79	4.55	16.1	37	81.8	3.6	11	40	93	205	
			3.6 V	2.04	4.9	16.8	38.7	85.6	3.9	12	42	97	214	
		RTC clocked by LSE quartz ⁽⁴⁾ in low drive mode, LCD disabled	1.8 V	1.43	3.99	14.7	35	-	3.2	10	37	88	-	
			2.4 V	1.54	4.11	15	35.8	-	3.3	10	38	90	-	
			3 V	1.67	4.29	15.5	36.7	-	3.4	11	39	92	-	
			3.6 V	1.87	4.57	16.2	38.3	-	3.7	11	41	96	-	
I _{DD} (wakeup from Stop2)	Supply current during wakeup from Stop 2 mode	Wakeup clock is MSI = 48 MHz, voltage Range 1. See ⁽⁵⁾ .	3 V	1.9	-	-	-	-	-					mA
		Wakeup clock is MSI = 4 MHz, voltage Range 2. See ⁽⁵⁾ .	3 V	2.24	-	-	-	-						
		Wakeup clock is HSI16 = 16 MHz, voltage Range 1. See ⁽⁵⁾ .	3 V	2.1	-	-	-	-						

1. Guaranteed by characterization results, unless otherwise specified.

Table 37. Current consumption in Standby mode (continued)

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (SRAM2) (⁴)	Supply current to be added in Standby mode when SRAM2 is retained	-	1.8 V	235	641	2293	5192	11213	588	1603	5733	12980	28033	nA
			2.4 V	237	645	2303	5213	11246	593	1613	5758	13033	28115	
			3 V	236	647	2306	5221	11333	593	1618	5765	13053	28333	
			3.6 V	235	646	2308	5200	11327	595	1620	5770	13075	28350	
I _{DD} (wakeup from Standby)	Supply current during wakeup from Standby mode	Wakeup clock is MSI = 4 MHz. See ⁽⁵⁾ .	3 V	1.7	-	-	-	-	-					mA

1. Guaranteed by characterization results, unless otherwise specified.
2. Guaranteed by test in production.
3. Based on characterization done with a 32.768 kHz crystal (MC306-G-06Q-32.768, manufacturer JFVNY) with two 6.8 pF loading capacitors.
4. The supply current in Standby with SRAM2 mode is: I_{DD}(Standby) + I_{DD}(SRAM2). The supply current in Standby with RTC with SRAM2 mode is: I_{DD}(Standby + RTC) + I_{DD}(SRAM2).
5. Wakeup with code execution from Flash. Average value given for a typical wakeup time as specified in [Table 41: Low-power mode wakeup timings](#).

Table 38. Current consumption in Shutdown mode

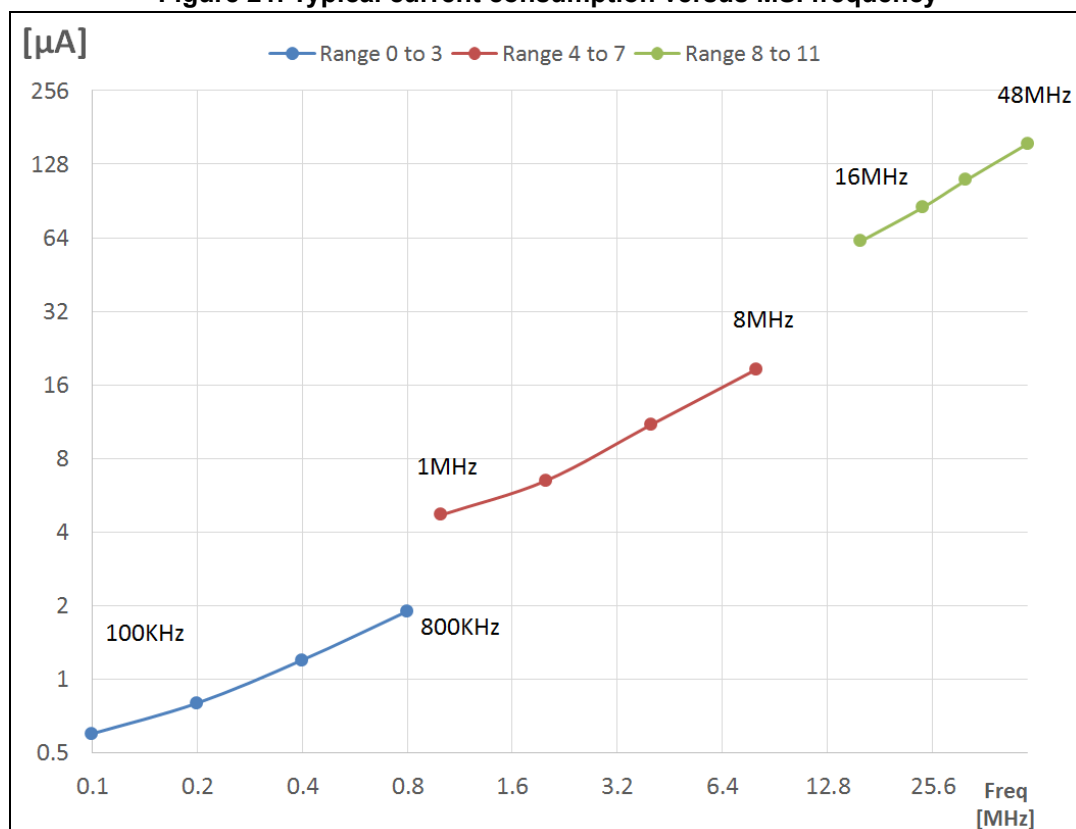
Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (Shutdown)	Supply current in Shutdown mode (backup registers retained) RTC disabled	-	1.8 V	29.8	194	1110	3250	9093	75	485	2775	8125	22733	nA
			2.4 V	44.3	237	1310	3798	10473	111	593	3275	9495	26183	
			3 V	64.1	293	1554	4461	12082	160	733	3885	11153	30205	
			3.6 V	112	420	2041	5689	15186	280	1050	5103	14223	37965	

Table 41. Low-power mode wakeup timings⁽¹⁾ (continued)

Symbol	Parameter	Conditions		Typ	Max	Unit
t _{WUSTOP1}	Wake up time from Stop 1 mode to Run mode in Flash	Range 1	Wakeup clock MSI = 48 MHz	6.2	10.2	µs
			Wakeup clock HSI16 = 16 MHz	6.3	8.99	
		Range 2	Wakeup clock MSI = 24 MHz	6.3	10.46	
			Wakeup clock HSI16 = 16 MHz	6.3	8.87	
			Wakeup clock MSI = 4 MHz	8.0	13.23	
	Wake up time from Stop 1 mode to Run mode in SRAM1	Range 1	Wakeup clock MSI = 48 MHz	4.5	5.78	
			Wakeup clock HSI16 = 16 MHz	5.5	7.1	
		Range 2	Wakeup clock MSI = 24 MHz	5.0	6.5	
			Wakeup clock HSI16 = 16 MHz	5.5	7.1	
			Wakeup clock MSI = 4 MHz	8.2	13.5	
	Wake up time from Stop 1 mode to Low-power run mode in Flash	Regulator in low-power mode (LPR=1 in PWR_CR1)	Wakeup clock MSI = 2 MHz	12.7	20	
	Wake up time from Stop 1 mode to Low-power run mode in SRAM1			10.7	21.5	
t _{WUSTOP2}	Wake up time from Stop 2 mode to Run mode in Flash	Range 1	Wakeup clock MSI = 48 MHz	8.0	9.4	µs
			Wakeup clock HSI16 = 16 MHz	7.3	9.3	
		Range 2	Wakeup clock MSI = 24 MHz	8.2	9.9	
			Wakeup clock HSI16 = 16 MHz	7.3	9.3	
			Wakeup clock MSI = 4 MHz	10.6	15.8	
	Wake up time from Stop 2 mode to Run mode in SRAM1	Range 1	Wakeup clock MSI = 48 MHz	5.1	6.7	
			Wakeup clock HSI16 = 16 MHz	5.7	8	
		Range 2	Wakeup clock MSI = 24 MHz	5.5	6.65	
			Wakeup clock HSI16 = 16 MHz	5.7	7.53	
			Wakeup clock MSI = 4 MHz	8.2	16.6	
t _{WUSTBY}	Wakeup time from Standby mode to Run mode	Range 1	Wakeup clock MSI = 8 MHz	14.3	20.8	µs
			Wakeup clock MSI = 4 MHz	20.1	35.5	
t _{WUSTBY SRAM2}	Wakeup time from Standby with SRAM2 to Run mode	Range 1	Wakeup clock MSI = 8 MHz	14.3	24.3	µs
			Wakeup clock MSI = 4 MHz	20.1	38.5	
t _{WUSHDN}	Wakeup time from Shutdown mode to Run mode	Range 1	Wakeup clock MSI = 4 MHz	256	330.6	µs

1. Guaranteed by characterization results.

Figure 21. Typical current consumption versus MSI frequency



Low-speed internal (LSI) RC oscillator

Table 50. LSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSI}	LSI Frequency	$V_{DD} = 3.0\text{ V}$, $T_A = 30\text{ °C}$	31.04	-	32.96	kHz
		$V_{DD} = 1.62\text{ to }3.6\text{ V}$, $T_A = -40\text{ to }125\text{ °C}$	29.5	-	34	
$t_{SU(LSI)}^{(2)}$	LSI oscillator start-up time	-	-	80	130	µs
$t_{STAB(LSI)}^{(2)}$	LSI oscillator stabilization time	5% of final frequency	-	125	180	µs
$I_{DD(LSI)}^{(2)}$	LSI oscillator power consumption	-	-	110	180	nA

1. Guaranteed by characterization results.

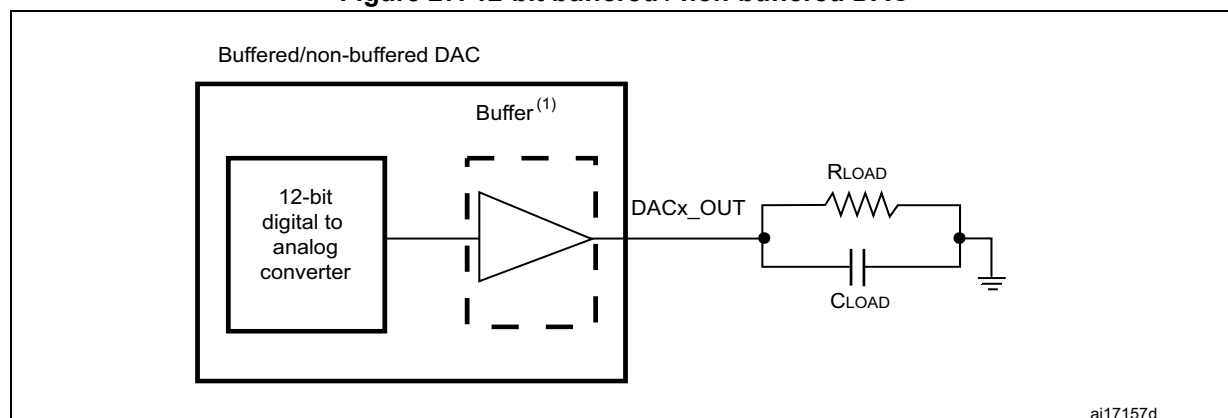
2. Guaranteed by design.

6.3.9 PLL characteristics

The parameters given in [Table 51](#) are derived from tests performed under temperature and V_{DD} supply voltage conditions summarized in [Table 22: General operating conditions](#).

4. Ton is the Refresh phase duration. Toff is the Hold phase duration. Refer to RM0351 reference manual for more details.

Figure 27. 12-bit buffered / non-buffered DAC



1. The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC_CR register.

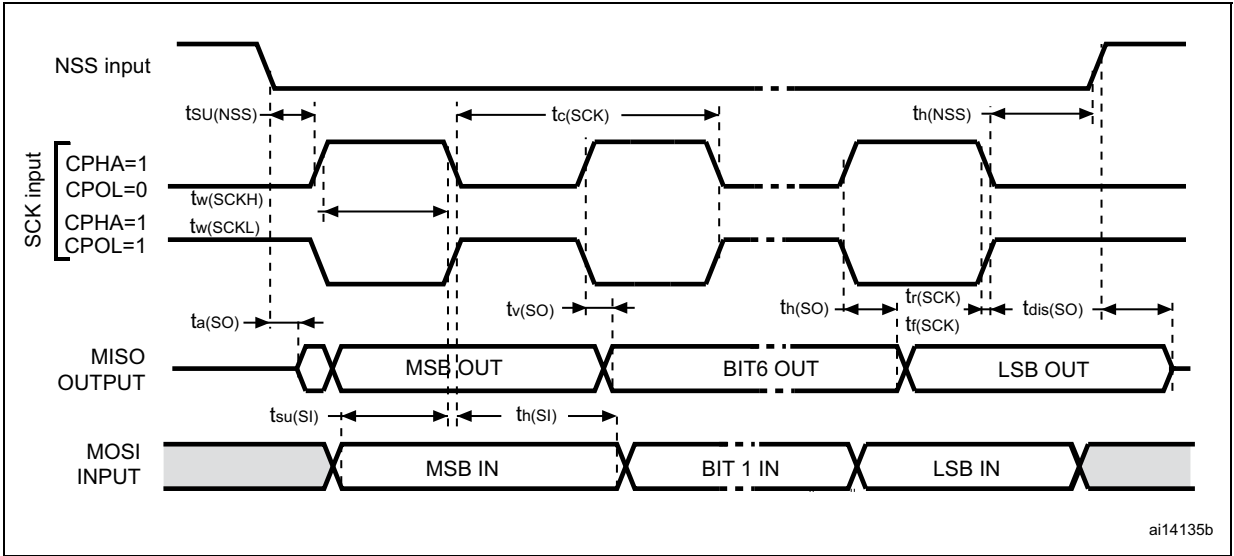
Table 71. DAC accuracy⁽¹⁾

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
DNL	Differential non linearity ⁽²⁾	DAC output buffer ON		-	-	±2	LSB
		DAC output buffer OFF		-	-	±2	
-	monotonicity	10 bits		guaranteed			
INL	Integral non linearity ⁽³⁾	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ		-	-	±4	
		DAC output buffer OFF CL ≤ 50 pF, no RL		-	-	±4	
Offset	Offset error at code 0x800 ⁽³⁾	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ	V _{REF+} = 3.6 V	-	-	±12	
			V _{REF+} = 1.8 V	-	-	±25	
		DAC output buffer OFF CL ≤ 50 pF, no RL		-	-	±8	
Offset1	Offset error at code 0x001 ⁽⁴⁾	DAC output buffer OFF CL ≤ 50 pF, no RL		-	-	±5	
OffsetCal	Offset Error at code 0x800 after calibration	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ	V _{REF+} = 3.6 V	-	-	±5	
			V _{REF+} = 1.8 V	-	-	±7	
Gain	Gain error ⁽⁵⁾	DAC output buffer ON CL ≤ 50 pF, RL ≥ 5 kΩ		-	-	±0.5	%
		DAC output buffer OFF CL ≤ 50 pF, no RL		-	-	±0.5	

Table 74. OPAMP characteristics⁽¹⁾ (continued)

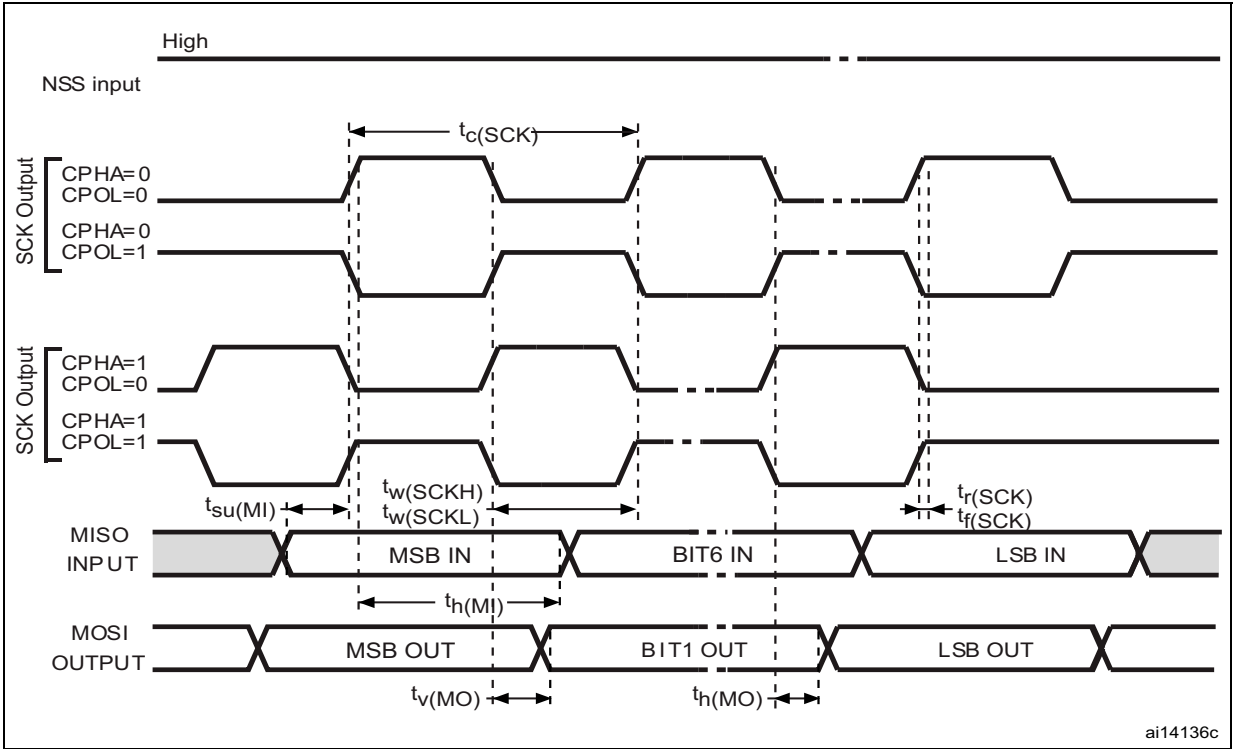
Symbol	Parameter	Conditions		Min	Typ	Max	Unit
PSRR	Power supply rejection ratio	Normal mode	C _{LOAD} ≤ 50 pf, R _{LOAD} ≥ 4 kΩ DC	70	85	-	dB
		Low-power mode	C _{LOAD} ≤ 50 pf, R _{LOAD} ≥ 20 kΩ DC	72	90	-	
GBW	Gain Bandwidth Product	Normal mode	V _{DDA} ≥ 2.4 V (OPA_RANGE = 1)	550	1600	2200	kHz
		Low-power mode		100	420	600	
		Normal mode	V _{DDA} < 2.4 V (OPA_RANGE = 0)	250	700	950	
		Low-power mode		40	180	280	
SR ⁽³⁾	Slew rate (from 10 and 90% of output voltage)	Normal mode	V _{DDA} ≥ 2.4 V	-	700	-	V/ms
		Low-power mode		-	180	-	
		Normal mode	V _{DDA} < 2.4 V	-	300	-	
		Low-power mode		-	80	-	
AO	Open loop gain	Normal mode		55	110	-	dB
		Low-power mode		45	110	-	
V _{OHSAT} ⁽³⁾	High saturation voltage	Normal mode	I _{load} = max or R _{load} = min Input at V _{DDA} .	V _{DDA} - 100	-	-	mV
		Low-power mode		V _{DDA} - 50	-	-	
V _{OLSAT} ⁽³⁾	Low saturation voltage	Normal mode	I _{load} = max or R _{load} = min Input at 0.	-	-	100	
		Low-power mode		-	-	50	
φ _m	Phase margin	Normal mode		-	74	-	°
		Low-power mode		-	66	-	
GM	Gain margin	Normal mode		-	13	-	dB
		Low-power mode		-	20	-	
t _{WAKEUP}	Wake up time from OFF state.	Normal mode	C _{LOAD} ≤ 50 pf, R _{LOAD} ≥ 4 kΩ follower configuration	-	5	10	μs
		Low-power mode	C _{LOAD} ≤ 50 pf, R _{LOAD} ≥ 20 kΩ follower configuration	-	10	30	
I _{bias}	OPAMP input bias current	Dedicated input (UFBGA132 only)	T _J ≤ 75 °C	-	-	1	nA
			T _J ≤ 85 °C	-	-	3	
			T _J ≤ 105 °C	-	-	8	
			T _J ≤ 125 °C	-	-	15	
		General purpose input (all packages except UFBGA132)			-	-	_(4)

Figure 29. SPI timing diagram - slave mode and CPHA = 1



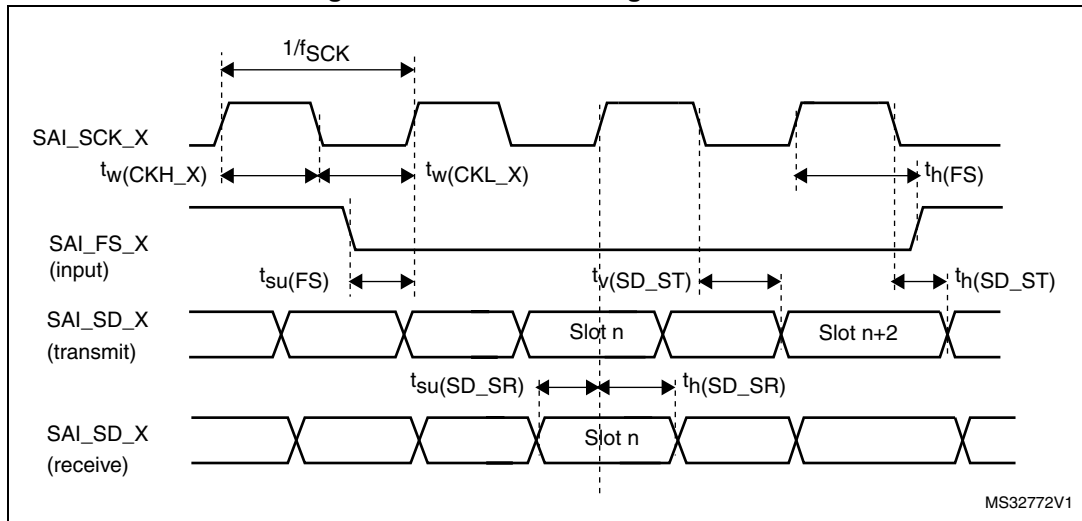
1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD} .

Figure 30. SPI timing diagram - master mode



1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD} .

Figure 34. SAI slave timing waveforms



SDMMC characteristics

Unless otherwise specified, the parameters given in [Table 88](#) for SDIO are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 22: General operating conditions](#), with the following configuration:

- Output speed is set to $OSPEEDRy[1:0] = 11$
- Capacitive load $C = 30$ pF
- Measurement points are done at CMOS levels: $0.5 \times V_{DD}$

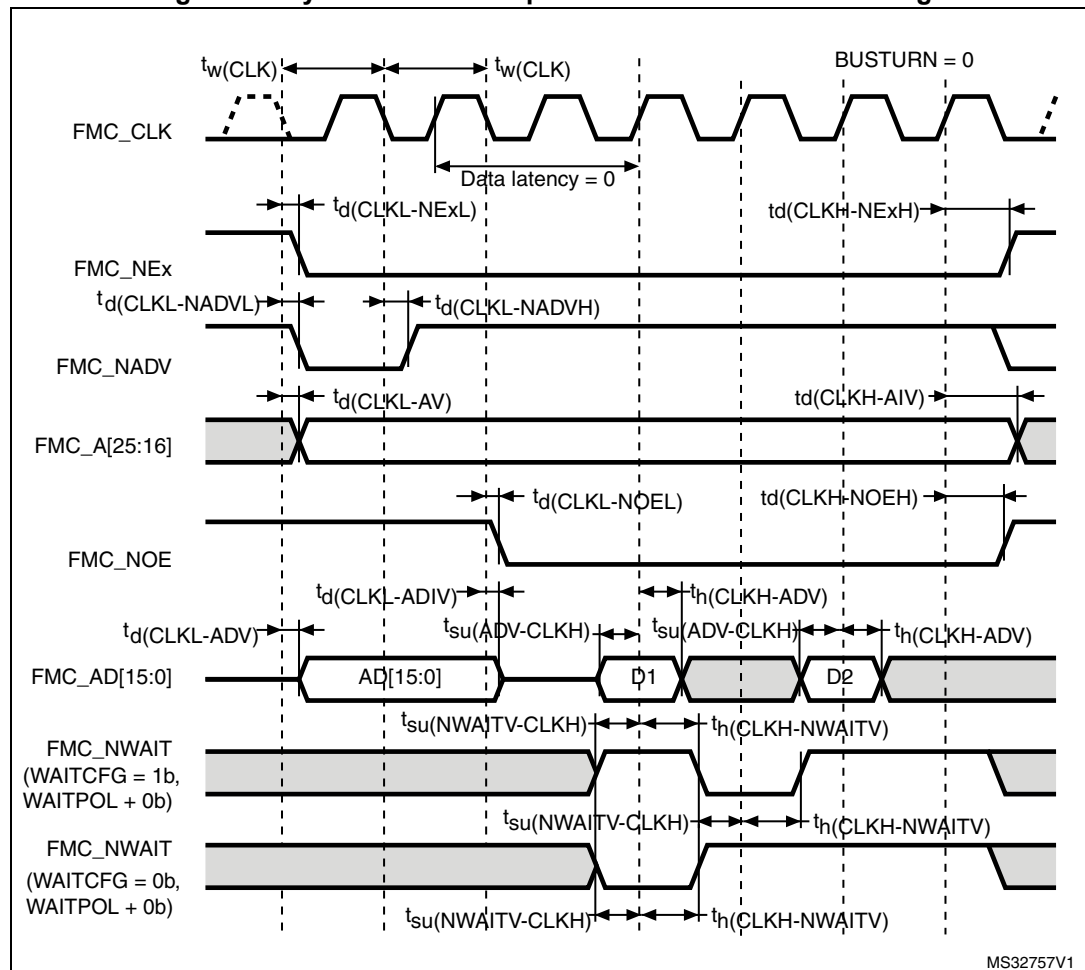
Refer to [Section 6.3.14: I/O port characteristics](#) for more details on the input/output characteristics.

Table 88. SD / MMC dynamic characteristics, $V_{DD}=2.7$ V to 3.6 V⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{PP}	Clock frequency in data transfer mode	-	0	-	50	MHz
-	SDIO_CK/fPCLK2 frequency ratio	-	-	-	4/3	-
$t_{W(CKL)}$	Clock low time	$f_{PP} = 50$ MHz	8	10	-	ns
$t_{W(CKH)}$	Clock high time	$f_{PP} = 50$ MHz	8	10	-	ns
CMD, D inputs (referenced to CK) in MMC and SD HS mode						
t_{ISU}	Input setup time HS	$f_{PP} = 50$ MHz	2	-	-	ns
t_{IH}	Input hold time HS	$f_{PP} = 50$ MHz	4.5	-	-	ns
CMD, D outputs (referenced to CK) in MMC and SD HS mode						
t_{OV}	Output valid time HS	$f_{PP} = 50$ MHz	-	12	14	ns
t_{OH}	Output hold time HS	$f_{PP} = 50$ MHz	9	-	-	ns
CMD, D inputs (referenced to CK) in SD default mode						
t_{ISUD}	Input setup time SD	$f_{PP} = 50$ MHz	2	-	-	ns
t_{IHD}	Input hold time SD	$f_{PP} = 50$ MHz	4.5	-	-	ns

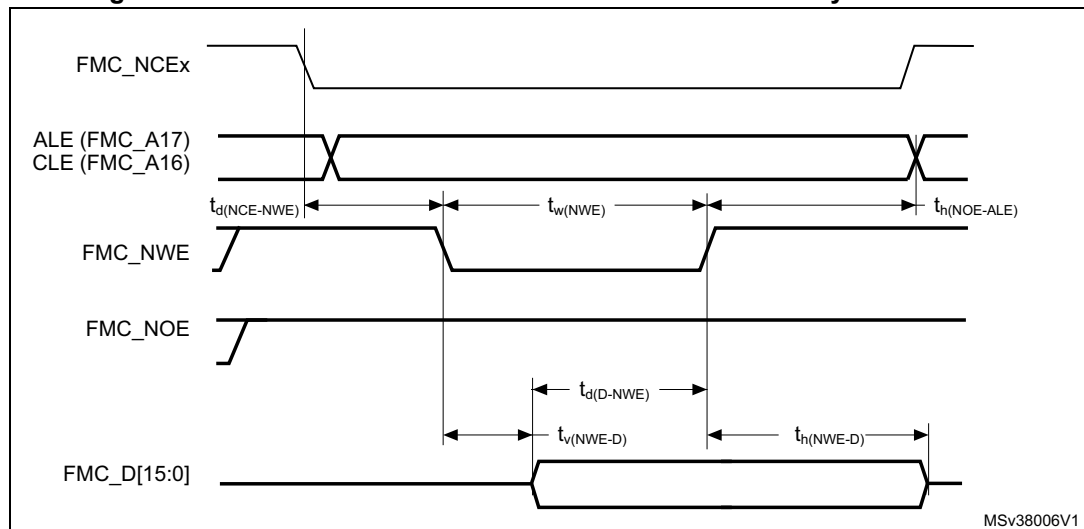
In all timing tables, the T_{HCLK} is the HCLK clock period.

Figure 41. Synchronous multiplexed NOR/PSRAM read timings



MS32757V1

Figure 48. NAND controller waveforms for common memory write access

Table 103. Switching characteristics for NAND Flash read cycles⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$T_{w(NOE)}$	FMC_NOE low width	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$T_{su(D-NOE)}$	FMC_D[15-0] valid data before FMC_NOE high	16	-	
$T_{h(NOE-D)}$	FMC_D[15-0] valid data after FMC_NOE high	6	-	
$T_{d(NCE-NOE)}$	FMC_NCE valid before FMC_NOE low	-	$3T_{HCLK}+1$	
$T_{h(NOE-ALE)}$	FMC_NOE high to FMC_ALE invalid	$2T_{HCLK}-2$	-	

1. CL = 30 pF.

2. Guaranteed by characterization results.

Table 104. Switching characteristics for NAND Flash write cycles⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$T_{w(NWE)}$	FMC_NWE low width	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$T_{v(NWE-D)}$	FMC_NWE low to FMC_D[15-0] valid	-	2.5	
$T_{h(NWE-D)}$	FMC_NWE high to FMC_D[15-0] invalid	$3T_{HCLK}-4$	-	
$T_{d(D-NWE)}$	FMC_D[15-0] valid before FMC_NWE high	$5T_{HCLK}-3$	-	
$T_{d(NCE-NWE)}$	FMC_NCE valid before FMC_NWE low	-	$3T_{HCLK}+1$	
$T_{h(NWE-ALE)}$	FMC_NWE high to FMC_ALE invalid	$2T_{HCLK}-2$	-	

1. CL = 30 pF.

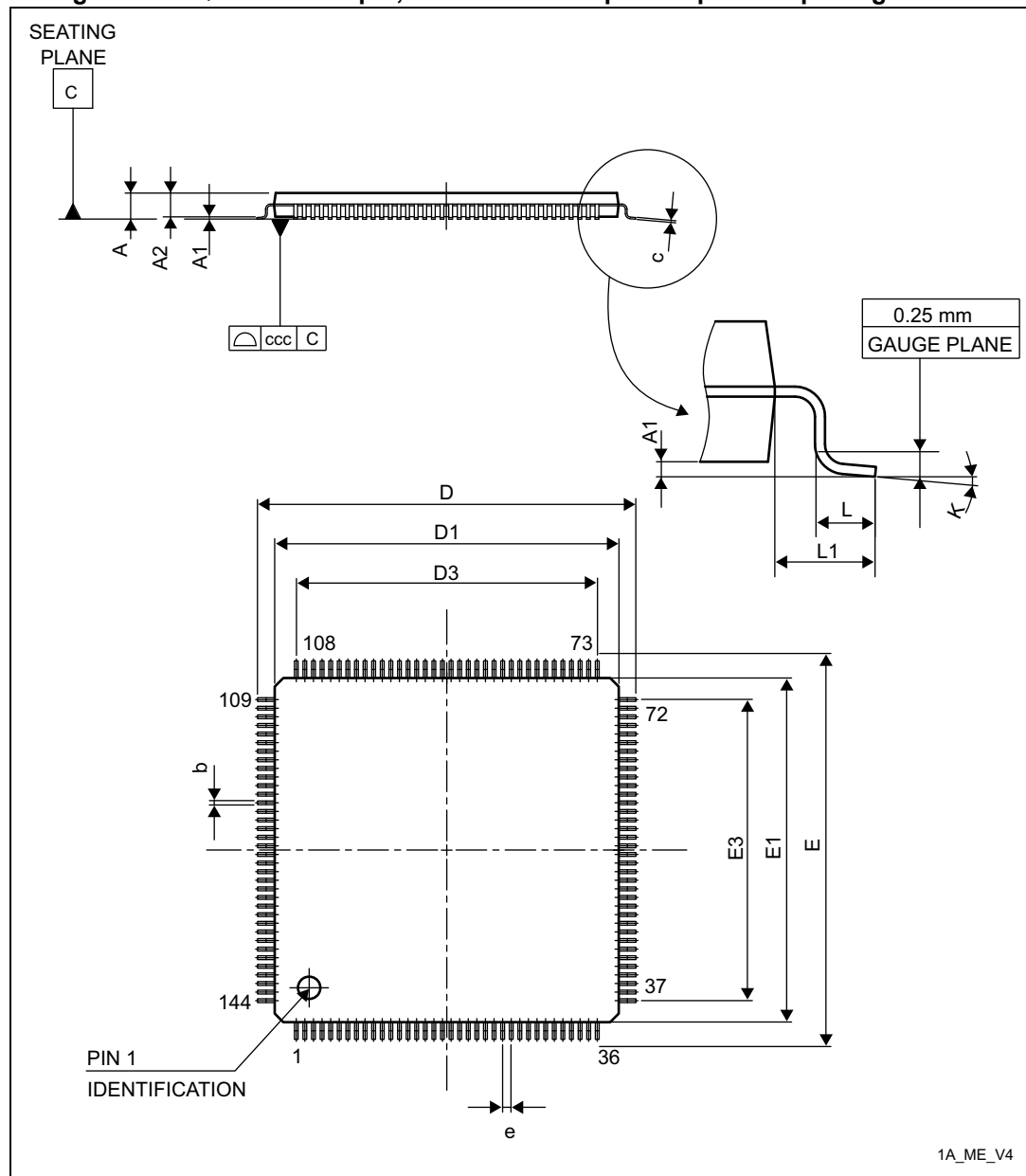
2. Guaranteed by characterization results.

7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

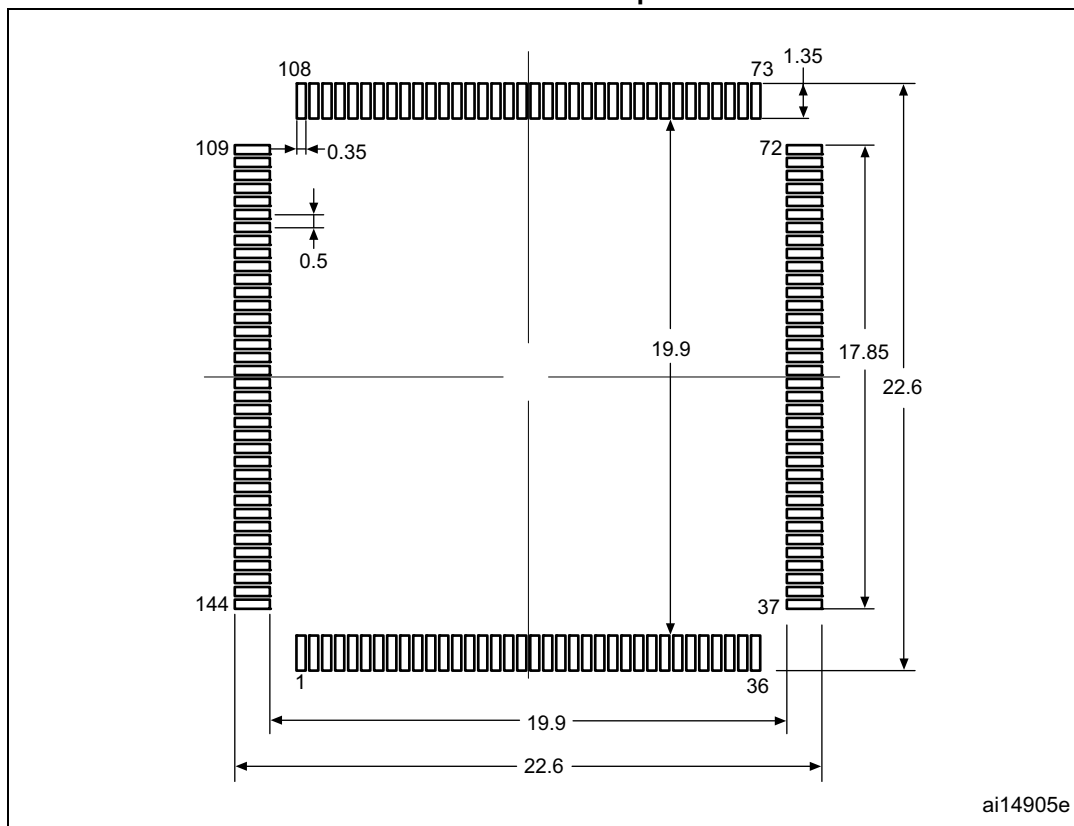
7.1 LQFP144 package information

Figure 49. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package outline



1. Drawing is not to scale.

Figure 50. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

9 Revision history

Table 115. Document revision history

Date	Revision	Changes
29-May-2015	1	Initial release.
12-Jun-2015	2	Updated Table 15: STM32L486xx pin definitions and Table 73: COMP characteristics .
18-Sep-2015	3	Changed alternate function pin name “SWDAT” into “SWDIO” in all the document. Updated Section 3.9.1: Power supply schemes. Updated Section 3.15.1: Temperature sensor. In all Section 6: Electrical characteristics, renamed table footnotes related to test and characterization. Added Note 2. Updated Table 41: Low-power mode wakeup timings. Updated Table 42: Regulator modes transition times. Updated Table 48: HSI16 oscillator characteristics. Added Table 20: HSI16 frequency versus temperature. Updated Table 49: MSI oscillator characteristics. Updated Table 50: LSI oscillator characteristics. Updated Table 58: I/O current injection susceptibility. Removed first Note in Table 59: I/O static characteristics. Removed second Note in Table 60: Output voltage characteristics. Updated Table 64: ADC characteristics. Updated Table 66: ADC accuracy - limited test conditions 1. Added Table 67: ADC accuracy - limited test conditions 2. Added Table 68: ADC accuracy - limited test conditions 3. Added Table 69: ADC accuracy - limited test conditions 4. Updated Table 71: DAC accuracy. Updated Table 72: VREFBUF characteristics. Added Section 6.3.25: DFSDM characteristics. Updated Section : Quad SPI characteristics. Updated Table 85: Quad SPI characteristics in SDR mode. Updated Table 86: QUADSPI characteristics in DDR mode. Updated Table 90: USB electrical characteristics. Updated Section 7.2: UFBGA132 package information. Updated Section 7.4: WLCSP72 package information. Updated Table 63: LQFP64 marking (package top view).